- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent $J-\overline{K}$ negative-edge-triggered flip-flops. A low level at the Preset or clear inputs sets or resets the outputs regardless of the levels of the other inputs. When Preset and Clear are inactive (high), data at the J and \overline{K} inputs meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and \overline{K} inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by grounding K and tying J high. They also can perform as D-type flip-flops if J and \overline{K} are tied together.

The SN54HC109 is characterized for operation over the full military temperature range of -55 °C to 125 °C. The SN74HC109 is characterized for operation from -40 °C to 85 °C.

F	UNC	TION	ТА	BLE
•	0140			

		INPUT	s		ουτι	PUTS
PRE	CLR	CLK	J	K	٥	ā
L	н	х	Х	х	н	L
н	L	х	х	х	L	н
L	L	х	х	х	H‡	H‡
н	н	t	L	L	L	н
н	н	t	Н	L	TOG	GLE
н	н	t	L	н	QO	<u>a</u> o
н	н	t	н	н	н	L
н	н	L	х	х	۵ ₀	ā0

[‡]This configuration is nonstable; that is, it will not persist when Preset or Clear return to their inactive (high) level.

SN54HC109, SN74HC109 DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH CLEAR AND PRESET

D2684, DECEMBER 1982-REVISED JUNE 1989

SN54HC109 J PACKAGE
SN74HC109 D OR N PACKAGE
(TOP VIEW)

1PRE 5 12 :	2K 2CLK 2PRE



NC-No internal connection

logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54HC109, SN74HC109 DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH CLEAR AND PRESET

logic diagram, each flip-flop (positive logic)



absolute maximum ratings over operating free-air temperature range[†]

Supply voltage, VCC · · · · · · · · · · · · · · · · · ·
Input clamp current, IIK (VI < 0 or VI > VCC) $\dots \dots \dots$
Output clamp current, I_{OK} (V _O < 0 or V _O > V _{CC} ± 20 mA
Continuous output current, IO (VO = 0 to VCC) $\dots \dots \dots$
Continuous current through VCC or GND pins ±50 mA
Lead temperature 1,6 mm (1/16 in) from case for 60 s: FK or J package
Lead temperature 1,6 mm (1/16 in) from case for 10 s: D or N package
Storage temperature range

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

			SI	SN54HC109			SN74HC109			
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		2	5	6	2	5_	6	V	
		$V_{CC} = 2 V$	1.5			1.5				
⊻н	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			v	
	-	$V_{CC} = 6 V$	4.2			4.2				
		$V_{CC} = 2 V$	0		0.3	0		0.3		
VIL	Low-level input voltage	$V_{CC} = 4.5 V$	0		0.9	0		0.9	v	
		$V_{CC} = 6 V$	0		1.2	0		1.2		
VI	Input voltage		0		Vcc	0		Vcc	V	
Vo	Output voltage		0		Vcc	0		Vcc	V	
		$V_{CC} = 2 V$	0		1000	0		1000		
t _t	Input transition (rise and fall) times	V _{CC} = 4.5 V	0		500	0		500	ns	
• ·		$V_{CC} = 6 V$	0		400	0		400		
TA	Operating free-air temperature		- 55		125	- 40		85	°C	

recommended operating conditions

$\begin{array}{c} \text{SN54HC109, SN74HC109} \\ \text{DUAL } J \overline{K} \text{ POSITIVE-EDGE-TRIGGERED} \\ \text{FLIP-FLOPS WITH CLEAR AND PRESET} \end{array}$

	TEAT CONDITIONS	N.	т	A = 25	°C	SN54	1C109	SN74H	IC109	UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	ТҮР	MAX	MIN	MAX	MIN	MAX	UNIT
		2 V	1.9	1.998		1.9		1.9		
	$V_{I} = V_{IH}$ or V_{IL} , $I_{OH} = -20 \ \mu A$	4.5 V	4.4	4.499		4.4		4.4		
∨он		6 V	5.9	5.999		5.9		5.9		V
	$V_{I} = V_{IH}$ or V_{IL} , $I_{OH} = -4$ mA	4.5 V	3.98	4.30		3.7		3.84		
	$V_{I} = V_{IH}$ or V_{IL} , $I_{OH} = -5.2$ mA	6 V	5.48	5.80		5.2		5.34		
		2 V		0.002	0.1		0.1		0.1	
	$V_{I} = V_{IH} \text{ or } V_{IL}, I_{OL} = 20 \ \mu \text{A}$	4.5 V		0.001	0.1		0.1		0.1	
VOL		6 V		0.001	0.1		0.1		0.1	V
	$V_I = V_{IH}$ or V_{IL} , $I_{OL} = 4 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	
	$V_{I} = V_{IH} \text{ or } V_{IL}, I_{OL} = 5.2 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
Ч	$V_{I} = V_{CC} \text{ or } 0$	6 V		±0.1	±100	. :	± 1000	E	±1000	nA
Icc	$V_I = V_{CC} \text{ or } 0, I_0 = 0$	6 V			4		80		40	μΑ
C ₁		2 to 6 V		3	10		10		10	pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

				тд =	25°C	SN54	HC109	SN74HC109		UNIT
				MIN	MAX	MIN	MAX	MIN	MAX	
f _{clock} Clock frequency			2 V	0	6	0	4.2	0	5	
			4.5 V	0	31	0	21	0	25	MHz
			6 V	0	36	0	25	0	29	
			2 V	100		150		125		
tw		PRE or CLR low	4.5 V	20		30		25		
			6 V	17		25		21		
	Pulse duration		2 V	80	<u> </u>	120	100		ns	
		CLK high or low	4.5 V	16		24		20		
			6 V	14		20		17		
			2 V	100		150		125		
		Data (J, K)	4.5 V	20		30		25		
	Setup time		6 V	17		25		21		
tsu	before CLK1		2 V	25		40	-	30		ns
		PRE or CLR	4.5 V	5		8		6		
		inactive	6 V	4		7		5		
		•	2 V	0		0		0		
th	Hold time, data after (CLKT	4.5 V	0		0		0		ns
			6 V	0		0		0		

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SN54HC109, SN74HC109 DUAL J-K POSITIVE-EDGE-TRIGGERED FLIP-FLOPS WITH CLEAR AND PRESET

switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $C_L = 50 \text{ pF}$ (see Note 1)

PARAMETER	FROM	то	Nee	Τŗ	= 25	= 25°C		SN54HC109		SN74HC109	
	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
			2 V	6	10		4.2		5		
f _{max}			4.5 V	31	50		21		25		MHz
			6 V	36	60		25		29		
			2 V		60	230		345		290	
tpd	PRE or CLR	Q or Q	4.5 V		15	46		69		58	ns
			6 V		12	39		59		49	
		_	2 V		50	175		250		220	
^t pd	CLK	QorQ	4.5 V		15	35		50		44	ns
			6 V		12	30		42		37	
			2 V		28	75		110		95	
tt		Q or Q	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	
Cpd	Power dissipatio	n capacitance per	flip-flop		N	o load, 1	A = 2!	5°C		35	pF typ

NOTE 1: Load circuit and voltage waveforms are shown in Section 1.

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